TOSHIBA PHOTOCOUPLER PHOTO RELAY

TLP209D

MEASUREMENT INSTRUMENTS LOGIC IC TESTERS / MEMORY TESTERS BOARD TESTERS / SCANNERS

The TOSHIBA TLP209D consist of a gallium arsenide infrared emitting diode optically coupled to a photo-MOS FET in a plastic SOP package. Its characteristics include low OFF-state current and low output pin capacitance, enabling it to be used in high-frequency measurement instruments.

Features

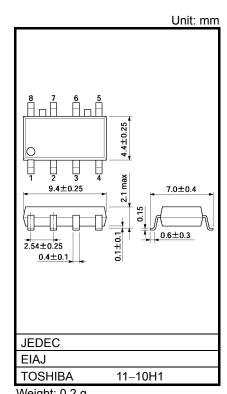
- 8 pin SOP (2.54SOP8)
- 2-Form-A
- ge :200 V (min)

: 2.1 mm high, 2.54 mm pitch

- Peak Off-State VoltageTrigger LED Current
- : 3 mA (max)
- : 50 mA (max)
- On-State Resistance : 50
- Output Capacitance
- Isolation Voltage

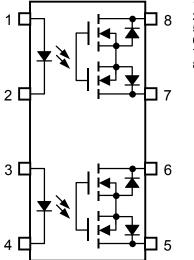
• On-State Current

- : 50 ohm (max) : 20 pF (max)
- : 1500 Vrms (min)



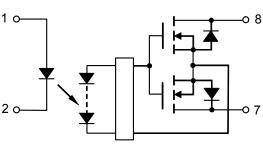
Weight: 0.2 g

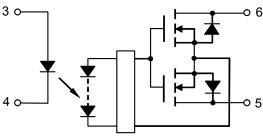
Pin Configuration (top view)



1, 3 : ANODE 2, 4 : CATHODE 5 : DRAIN D1 6 : DRAIN D2 7 : DRAIN D3 8 : DRAIN D4

Schematic





Absolute Maximum Ratings (Ta = 25°C)

	CHARACTERISTIC	SYMBOL	RATING	UNIT
D	Forward Current	lF	50	mA
	Forward Current Derating (Ta \ge 25°C)	∆I _F /°C	-0.5	mA/°C
LED	Reverse Voltage	V _R	5	V
	Junction Temperature	Tj	125	°C
ц	Off-State Output Terminal Voltage	V _{OFF}	200	V
DETECTOR	On-State Current	I _{ON}	50	mA
	On-State Current Derating (Ta \ge 25°C)	∆l _{ON} /°C	-0.5	mA/°C
	Junction Temperature	Tj	125	°C
Stora	ige Temperature Range	T _{stg}	-55~125	°C
Oper	ating Temperature Range	T _{opr}	-40~85	°C
Lead	Soldering Temperature (10 s)	T _{sol}	260	°C
Isola	tion Voltage (AC, 1 minute, R.H. \leq 60%) (NOTE1)	BVS	1500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(NOTE1): Device considered a two-terminal device : LED side pins shorted together, and DETECTOR side pins shorted together.

Recommended Operating Conditions

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Supply Voltage	V _{DD}			160	V
Forward Current	١ _F	5	7.5	15	mA
On-State Current	I _{ON}	_	_	50	mA
Operating Temperature	T _{opr}	-20		60	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Individual Electrical Characteristics (Ta = 25°C)

	CHARACTERISTIC	SYMBOL	TEST CONDITION	Min	Тур.	Max	UNIT
	Forward Voltage	V _F	I _F = 10 mA	1.0	1.15	1.3	V
LED	Reverse Current	I _R	$V_R = 5 V$	—	_	10	μA
	Capacitance	CT	V = 0, f = 1 MHz	_	30		pF
CTOR	Off-State Current	IOFF	V _{OFF} = 160 V	—		1	nA
DETECT	Capacitance	C _{OFF}	V = 0, f = 1 MHz	_	15	20	pF

Coupled Electrical Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Min	Тур.	Max	UNIT
Trigger LED Current	I _{FT}	I _{ON} = 50 mA		1	3	mA
Return LED Current	I _{FC}	I _{OFF} = 100 μA	0.1	_	_	mA
On-State Resistance	R _{ON}	$I_{ON} = 50 \text{ mA}, I_F = 5 \text{ mA}$		40	50	Ω

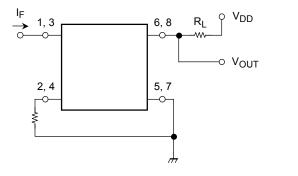
Isolation Characteristics (Ta = 25°C)

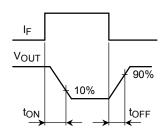
CHARACTERISTIC	SYMBOL	TEST CONDITION	Min	Тур.	Max	UNIT
Capacitance Input to Output	CS	$V_{S} = 0 V$, f = 1 MHz	_	0.8	_	pF
Isolation Resistance	R _S	$V_{S} = 500 \text{ V}, \text{ R.H.} \le 60\%$	$5 imes 10^{10}$	10 ¹⁴	_	Ω
	BVS	AC, 1 minute	1500	_	_	Vrms
Isolation Voltage		AC, 1 second (in oil)	_	3000	_	VIIIS
		DC, 1 minute (in oil)	—	3000	_	Vdc

Switching Characteristics (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION		Тур.	Max	UNIT
Turn-on Time	t _{ON}	$R_L = 200 \Omega$ (NO	ΓE 2) —	0.03	0.5	ms
Turn-off Time	tOFF	V _{DD} = 10 V, I _F = 5 mA	_	0.07	0.2	1115

(NOTE 2) : SWITCHING TIME TEST CIRCUIT





RESTRICTIONS ON PRODUCT USE

20070701-EN

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- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
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